## Applicant(s)/Patent Under Application/Control No. Reexamination 10/787,326 STENZ ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2825 Vuthe Siek **U.S. PATENT DOCUMENTS** Date **Document Number** Classification Name Country Code-Number-Kind Code MM-YYYY Singh et al. 716/16 US-6,779,169 08-2004 Α \* 716/9 US-6,415,426 07-2002 Chang et al. В US-С US-D US-Ε F US-US-G US-Н US-

## FOREIGN PATENT DOCUMENTS

TOTALIST POODMETT							
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification	
	N						
	0						
	Р	,				-	
	Q						
	R						
	S						
	Т						

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	v	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

1

Κ

М

US-US-

US-US-